- 1 Supplementary Material: Controlled low dimensionality in hybrid
- 2 organic-inorganic superlattices

3

- 4 One-dimensional electron density map calculated from XRD results
- 5 X-ray diffraction spectrum reflects the electronic and atomic structure information of
- 6 the material, which can be reversed from the XRD results.
- 7 The electron density along the c-axis could be obtained by

8

$$\rho(z) = \sum_{j=1}^{\infty} F_{00l} \cos\left(\frac{2\pi lz}{c}\right)$$
 (S1)

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- where l, F<sub>001</sub>, and c represents the Miller index of the (001) crystal plane, structure factor
- of the 00l reflections, and the interlayer distances, respectively.
- 12 The structure factors of the 001 reflections  $F_{001}$  were derived from their intensities
- 13 corrected for Lorentz-polarization effects

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$$|F_{00I}| = (I/Lp)^{1/2} \tag{S2}$$

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- where I is the intensity of the peak intensity and  $L_p$  is the Lorentz-polarization factor
- which can be written as

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$$Lp = (1 + \cos^2 2\theta) / (\sin^2 \theta \cos \theta)$$
 (S3)

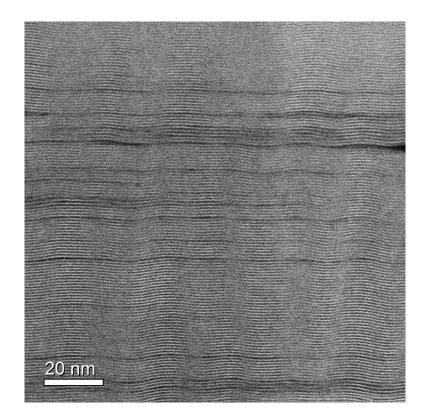
19

- The absolute values for  $F_{001}$  can be derived by Eq. (4). The signs (phase) of the structure
- 21 factor can be directly obtained instead from the scattering contributions of the inorganic
- 22 atoms framework by assuming that the contribution from the intercalated organic
- 23 molecules is relatively small.

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$$F_{00l} = \sum_{j=1}^{N} 2f_i \cos(2\pi l z_i)$$
 (S4)

where  $f_i$  is the scattering factor of j atom,  $z_i$  is its fractional coordinate on the c axis. Using Eq. (5), the sign for each  $F_{001}$  was determined and combined with the absolute value in Eq. (4), and the one dimensional electron density map can be derived.



Supplementary Figure 4. HAADF-STEM figure of TiS<sub>2</sub>/HA/H<sub>2</sub>O